## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination HWANG ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0165496	08-2004	Park et al.	369/047.14
*	В	US-6,469,978	10-2002	Ohata et al.	369/275.3
*	С	US-2002/0136537	09-2002	Takahashi, Hideki	386/95
*	D	US-6,564,345	05-2003	Kim et al.	714/723
*	F	US-6,160,778	12-2000	Ito et al.	369/53.15
	F	U\$-			
	G	US-	,		
	Н	US-			
	ı	US-			
	J	US-			
	К	US-		·	
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Ρ					
	σ					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYYY format are publication dates. Classif ications may be US or foreign.